

ACPL-077L

Low-Power 3.3V/5V High-Speed CMOS Optocoupler Design for System-Level Reliability

Description

The Broadcom[®] ACPL-077L optocoupler utilizes the latest CMOS IC technology to achieve outstanding speed and low power performance of minimum 25-MBd data rate and 6-ns maximum pulse width distortion with enhanced reliability relative to system-level IEC 61000-4-X testing (ESD/Burst/Surge).

Available in SO-8 package, the basic building blocks of ACPL-077L are a CMOS LED driver IC, a high-speed LED, and a CMOS detector IC. A CMOS logic input signal controls the LED driver IC, which supplies current to the LED. The detector IC incorporates an integrated photodiode, a high-speed transimpedance amplifier, and a voltage comparator with an output driver.

CAUTION! It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation, which may be induced by ESD. The components featured in this data sheet are not to be used in military or aerospace applications or environments.

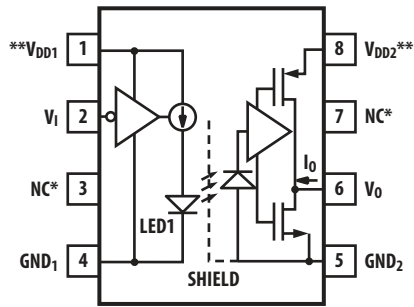
Features

- Enhance reliability relative to system-level IEC 61000-4-X testing (ESD/Burst/Surge)
- 3.3V and 5V CMOS compatibility
- CMOS buffer input
- Allow level shifting functionality
- High speed: DC to 25 MBd
- 35-kV/ μ s minimum common mode rejection (CMR) at $V_{CM} = 1000V$
- Guaranteed AC and DC performance over wide temperature: -40 to $+105^{\circ}C$
- Safety and regulatory approvals:
 - UL recognized:
 - $3750 V_{rms}$ for 1 min. per UL1577
 - CSA component acceptance notice #5
 - IEC/EN/DIN EN 60747-5-5:
 - $V_{IORM} = 567 V_{peak}$ for Option 060E
- Lead-free option available

Applications

- Digital fieldbus isolation: CC-Link, DeviceNet, Profibus, SDS
- Multiplexed data transmission
- General instrument and data acquisition
- Computer peripheral interface
- Microprocessor system interface

Functional Diagram



* Pin 3 is multiplexed as a test pin that can connect to V_{DD} or left unconnected. Pin 7 is not connected internally.

** A 0.01 μF to 0.1 μF bypass capacitor must be connected as close as possible between pins V_{DD1} and GND_1 , and V_{DD2} and GND_2 .

Truth Table

| V_I | LED1 | V_O |
|-------|------|-------|
| HIGH | OFF | HIGH |
| LOW | ON | LOW |

Ordering Information

ACPL-077L is UL Recognized with 3750 V_{rms} for 1 minute per UL1577.

| Part Number | Option | Package | Surface Mount | Tape and Reel | IEC/EN/DIN EN 60747-5-5 | Quantity |
|-------------|----------------|---------|---------------|---------------|-------------------------|---------------|
| | RoHS Compliant | | | | | |
| ACPL-077L | -000E | SO-8 | X | | | 100 per tube |
| | -060E | | X | | X | 100 per tube |
| | -500E | | X | X | | 1500 per reel |
| | -560E | | X | X | X | 1500 per reel |

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

Example 1:

ACPL-077L-500E to order product of Mini-flat Surface Mount 8-pin package in Tape and Reel packaging with RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information.

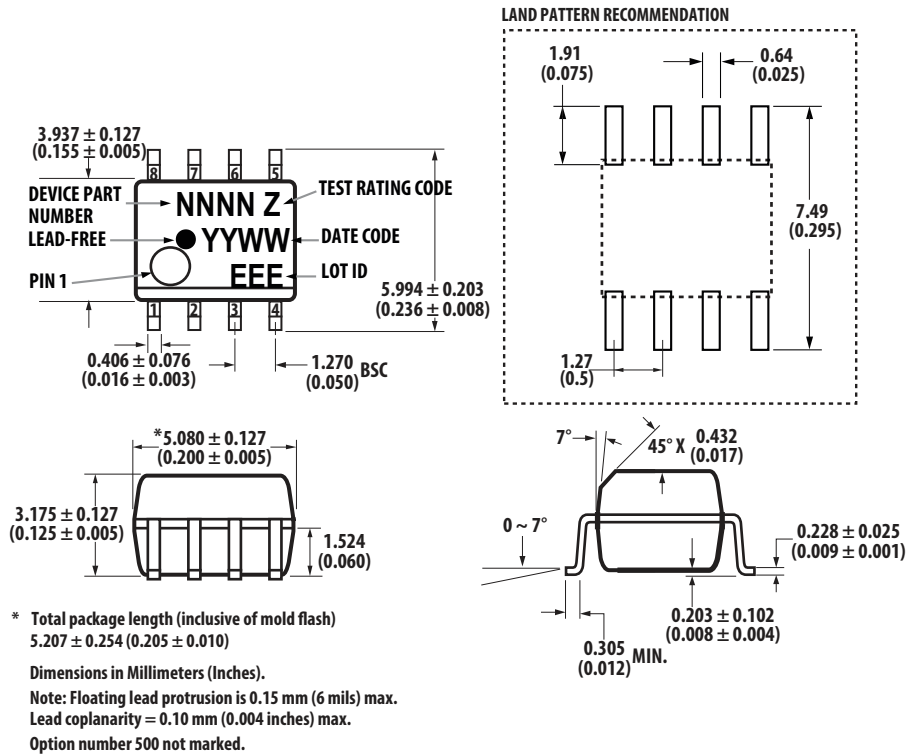
Regulatory Information

The ACPL-077L will be approved by the following organizations:

- **UL** — Approval under UL 1577, component recognition program up to $V_{\text{ISO}} = 3750 V_{\text{RMS}}$.
- **CSA** — Approval under CSA component acceptance notice #5.
- **IEC/EN/DIN EN 60747-5-5** — (Option 060E only)

Package Outline Drawings

ACPL-077L SO-8 Package



Solder Reflow Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision). Non-Halide Flux should be used.

Insulation and Safety Related Specifications

| Parameter | Symbol | ACPL-077L | Unit | Conditions |
|---|--------|-----------|------|--|
| Minimum External Air Gap (Clearance) | L(I01) | 4.9 | mm | Measured from input terminals to output terminals, shortest distance through air. |
| Minimum External Tracking (Creepage) | L(I02) | 4.8 | mm | Measured from input terminals to output terminals, shortest distance path along body. |
| Minimum Internal Plastic Gap (Internal Clearance) | | 0.08 | mm | Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector. |
| Tracking Resistance (Comparative Tracking Index) | CTI | 175 | V | DIN IEC 112/VDE 0303 Part 1. |
| Isolation Group | | IIIa | | Material Group (DIN VDE 0110, 1/89, Table 1). |

IEC/EN/DIN EN 60747-5-5 Insulation Characteristics (Option 060E)

| Description | Symbol | Characteristic | Unit |
|---|---------------|-----------------------------|-------------|
| | | ACPL-077L | |
| Installation Classification per DIN VDE 0110/39, Table 1 For Rated Mains Voltage $\leq 150V_{rms}$ For Rated Mains Voltage $\leq 300V_{rms}$ For Rated Mains Voltage $\leq 600V_{rms}$ | | I – IV I – III I – II | |
| Climatic Classification | | 55/105/21 | |
| Pollution Degree (DIN VDE 0110/39) | | 2 | |
| Maximum Working Insulation Voltage | V_{IORM} | 567 | V_{peak} |
| Input to Output Test Voltage, Method b ^a $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with $t_m = 1s$, Partial Discharge $< 5 pC$ | V_{PR} | 1063 | V_{peak} |
| Input to Output Test Voltage, Method a ^a $V_{IORM} \times 1.6 = V_{PR}$, Type and Sample Test, $t_m = 10s$, Partial Discharge $< 5 pC$ | V_{PR} | 907 | V_{peak} |
| Highest Allowable Overvoltage (Transient Overvoltage $t_{ini} = 60s$) | V_{IOTM} | 6000 | V_{peak} |
| Safety-Limiting Values – Maximum Values Allowed in the Event of a Failure | | | |
| Case Temperature | T_S | 150 | $^{\circ}C$ |
| Input Current ^b | $I_S, INPUT$ | 150 | mA |
| Output Power | $P_S, OUTPUT$ | 600 | mW |
| Insulation Resistance at T_S , $V_{IO} = 500V$ | R_S | $\geq 10^9$ | Ω |

a. Refer to the optocoupler section of the Isolation and Control Component Designer's Catalog, under Product Safety Regulations section (IEC/EN/DIN EN 60747-5-5) for a detailed description of Method a and Method b partial discharge test profiles.

b. Refer to figure 10 for dependence of P_S and I_S on ambient temperature.

NOTE: These optocouplers are suitable for *safe electrical isolation* only within the safety limit data. Maintenance of the safety data is ensured by means of protective circuits.

Absolute Maximum Ratings

| Parameter | Symbol | Min. | Max. | Unit |
|-----------------------------------|--|--|-----------------|------|
| Storage Temperature | T_S | -55 | 125 | °C |
| Operating Temperature | T_A | -40 | 105 | °C |
| Supply Voltages | V_{DD1}, V_{DD2} | 0 | 6.5 | V |
| Input Voltage | V_I | -0.5 | $V_{DD1} + 0.5$ | V |
| Output Voltage | V_O | -0.5 | $V_{DD2} + 0.5$ | V |
| Average Output Current | I_O | — | 10 | mA |
| Lead Solder Temperature | T_{LS} | 260° C for 10 sec., 1.6 mm below seating plane | | |
| Solder Reflow Temperature Profile | See Solder Reflow Profile section. | | | |

Recommended Operating Conditions

| Parameter | Symbol | Min. | Max. | Unit |
|----------------------------------|--------------------|----------------------|----------------------|------|
| Operating Temperature | T_A | -40 | 105 | °C |
| Supply Voltages (3.3V) | V_{DD1}, V_{DD2} | 3.0 | 3.6 | V |
| Supply Voltages (5V) | V_{DD1}, V_{DD2} | 4.5 | 5.5 | V |
| Logic High Input Voltage | V_{IH} | $0.7 \times V_{DD1}$ | V_{DD1} | V |
| Logic Low Input Voltage | V_{IL} | 0 | $0.3 \times V_{DD1}$ | V |
| Input Signal Rise and Fall Times | t_{ir}, t_{if} | — | 1.0 | ms |

Electrical Specifications

Over recommended temperature ($T_A = -40^\circ\text{C}$ to 105°C) and supply voltage ($4.5\text{V} \leq V_{DD1} \leq 5.5\text{V}$, $4.5\text{V} \leq V_{DD2} \leq 5.5\text{V}$), ($3\text{V} \leq V_{DD1} \leq 3.6\text{V}$, $3\text{V} \leq V_{DD2} \leq 3.6\text{V}$), ($4.5\text{V} \leq V_{DD1} \leq 5.5\text{V}$, $3\text{V} \leq V_{DD2} \leq 3.6\text{V}$) and ($3\text{V} \leq V_{DD1} \leq 3.6\text{V}$, $4.5\text{V} \leq V_{DD2} \leq 5.5\text{V}$). All typical specifications are at $V_{DD1} = V_{DD2} = +3.3\text{V}$, $T_A = 25^\circ\text{C}$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions |
|--|------------|------|------|------|------|--|
| Logic Low Input Supply Current ^a | I_{DD1L} | — | 5.5 | 8 | mA | $V_I = 0\text{V}$; Figure 1 |
| Logic High Input Supply Current ^a | I_{DD1H} | — | 0.6 | 2 | mA | $V_I = V_{DD1}$; Figure 2 |
| Logic Low Output Supply Current | I_{DD2L} | — | 1.5 | 2.5 | mA | $V_I = 0\text{V}$; Figure 3 |
| Logic High Output Supply Current | I_{DD2H} | — | 1.5 | 2.5 | mA | $V_I = V_{DD1}$; Figure 4 |
| Input Current | I_I | -10 | — | 10 | μA | |
| Logic High Output Voltage | V_{OH} | 2.9 | 3.3 | — | V | $I_O = -20 \mu\text{A}$, $V_I = V_{IH}$, $V_{DD2} = 3.3\text{V}$ |
| | | 1.9 | 2.9 | — | V | $I_O = -4 \text{mA}$, $V_I = V_{IH}$, $V_{DD2} = 3.3\text{V}$ |
| | | 4.0 | 4.7 | — | V | $I_O = -4 \text{mA}$, $V_I = V_{IH}$, $V_{DD2} = 5.0\text{V}$ |
| Logic Low Output Voltage | V_{OL} | — | 0 | 0.1 | V | $I_O = 20 \mu\text{A}$, $V_I = V_{IL}$ |
| | | — | 0.35 | 1.0 | V | $I_O = 4 \text{mA}$, $V_I = V_{IL}$ |

a. The LED is ON when V_I is low and OFF when V_I is high.

Switching Specifications

Over recommended temperature ($T_A = -40^\circ\text{C}$ to 105°C) and supply voltage ($4.5\text{V} \leq V_{DD1} \leq 5.5\text{V}$, $4.5\text{V} \leq V_{DD2} \leq 5.5\text{V}$), ($3\text{V} \leq V_{DD1} \leq 3.6\text{V}$, $3\text{V} \leq V_{DD2} \leq 3.6\text{V}$), ($4.5\text{V} \leq V_{DD1} \leq 5.5\text{V}$, $3\text{V} \leq V_{DD2} \leq 3.6\text{V}$) and ($3\text{V} \leq V_{DD1} \leq 3.6\text{V}$, $4.5\text{V} \leq V_{DD2} \leq 5.5\text{V}$). All typical specifications are at $V_{DD1} = V_{DD2} = +3.3\text{V}$, $T_A = 25^\circ\text{C}$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions |
|--|-----------|------|------|------|-------------------|---|
| Propagation Delay Time to Logic Low Output ^a | t_{PHL} | — | 24 | 40 | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels; Figure 5 and Figure 6 . |
| Propagation Delay Time to Logic High Output ^a | t_{PLH} | — | 23 | 40 | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels; Figure 5 and Figure 6 . |
| Pulse Width | t_{PW} | 40 | — | — | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels. |
| Maximum Data Rate | | — | — | 25 | MBd | $C_L = 15\text{ pF}$, CMOS Signal Levels. |
| Pulse Width Distortion ^b $ t_{PHL} - t_{PLH} $ | $ PWD $ | — | 1 | 6 | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels; Figure 7 and Figure 8 . |
| Propagation Delay Skew ^c | t_{PSK} | — | — | 15 | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels. |
| Output Rise Time (10% to 90%) | t_R | — | 4 | — | ns | $C_L = 15\text{ pF}$, CMOS Signal Levels, Figure 9 . |
| Output Fall Time (90% to 10%) | t_F | — | 3 | — | ns | |
| Common Mode Transient Immunity at Logic High Output ^d | $ CM_H $ | 35 | 50 | — | kV/ μs | $V_{CM} = 1000\text{V}$, $T_A = 25^\circ\text{C}$, $V_I = V_{DD1}$, $V_O > 0.8 \times V_{DD2}$. |
| Common Mode Transient Immunity at Logic Low Output ^d | $ CM_L $ | 35 | 50 | — | kV/ μs | $V_{CM} = 1000\text{V}$, $T_A = 25^\circ\text{C}$, $V_I = 0\text{V}$, $V_O < 0.8\text{V}$. |

- t_{PHL} propagation delay is measured from the 50% level on the falling edge of the V_I signal to the 50% level of the falling edge of the V_O signal. t_{PLH} propagation delay is measured from the 50% level on the rising edge of the V_I signal to the 50% level of the rising edge of the V_O signal.
- PWD is defined as $|t_{PHL} - t_{PLH}|$. %PWD (percent pulse width distortion) is equal to the PWD divided by pulse width.
- t_{PSK} is equal to the magnitude of the worst-case difference in t_{PHL} and/or t_{PLH} that will be seen between units at any given temperature within the recommended operating conditions.
- CM_H is the maximum common mode voltage slew rate that can be sustained while maintaining $V_O > 0.8 V_{DD2}$. CM_L is the maximum common mode voltage slew rate that can be sustained while maintaining $V_O < 0.8\text{V}$. The common mode voltage slew rates apply to both rising and falling common mode voltage edges.

Package Characteristics

All typical specifications are at $T_A = 25^\circ\text{C}$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions |
|--|-----------|------|-----------|------|-----------|--|
| Input-Output Insulation ^{a, b, c} | V_{ISO} | 3750 | — | — | V_{RMS} | $RH \leq 50\%$ for 1 min, $T_A = 25^\circ\text{C}$ |
| Input-Output Resistance ^a | R_{I-O} | — | 10^{12} | — | Ω | $V_{I-O} = 500\text{V}$ |
| Input-Output Capacitance | C_{I-O} | — | 0.6 | — | pF | $f = 1\text{ MHz}$, $T_A = 25^\circ\text{C}$ |
| Input Capacitance ^d | C_I | — | 3.0 | — | pF | |

- Device considered a two-terminal device: pins 1, 2, 3, and 4 shorted together and pins 5, 6, 7, and 8 shorted together.
- In accordance with UL1577, each ACPL-077L is proof tested by applying an insulation test voltage $\geq 4500 V_{RMS}$ for 1 second (leakage detection current limit, $I_{I-O} \leq 5\ \mu\text{A}$).
- The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating. For the continuous voltage rating, refer to your equipment level safety specification or Broadcom Application Note 1074, Optocoupler Input-Output Endurance Voltage.
- C_I is the capacitance measured at pin 2 (V_I).

Figure 1: Typical Logic Low Input Supply Current vs. Temperature

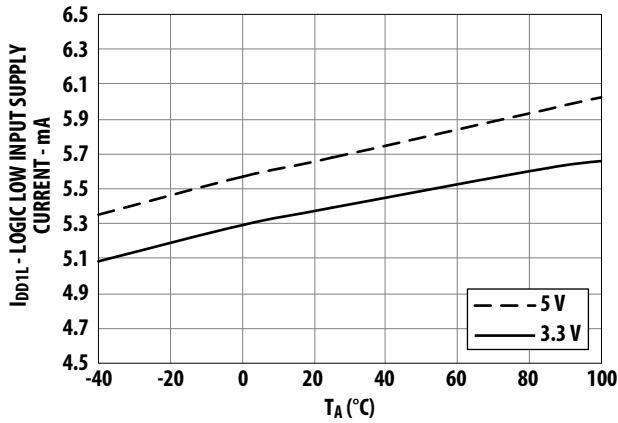


Figure 2: Typical Logic High Input Supply Current vs. Temperature

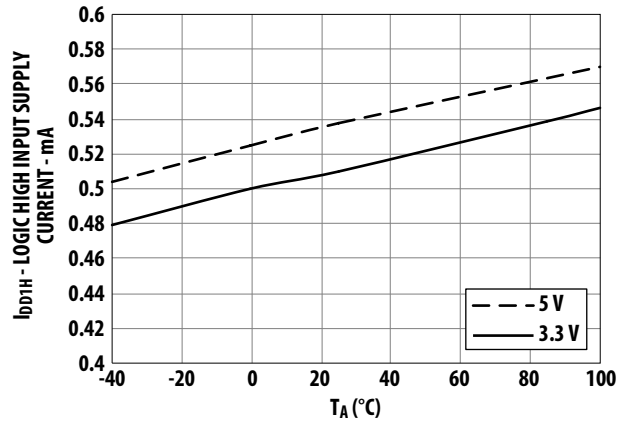


Figure 3: Typical Logic Low Output Supply Current vs. Temperature

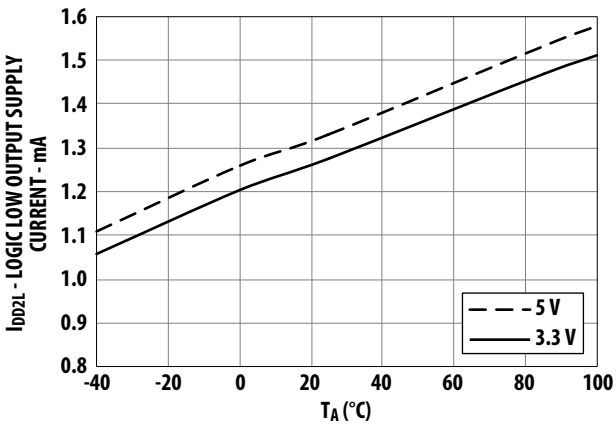


Figure 4: Typical Logic High Output Supply Current vs. Temperature

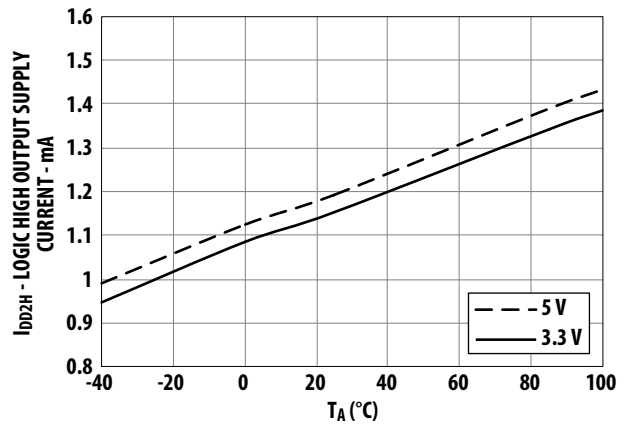


Figure 5: Typical Propagation Delay vs. Temperature at 3.3V Supply Voltage

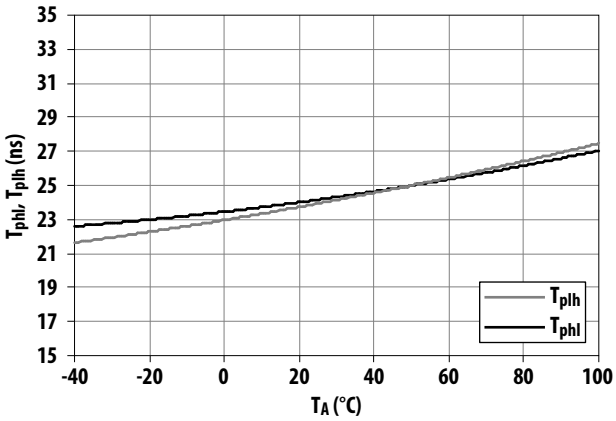


Figure 6: Typical Propagation Delays vs. Load Capacitance at 3.3V Supply Voltage

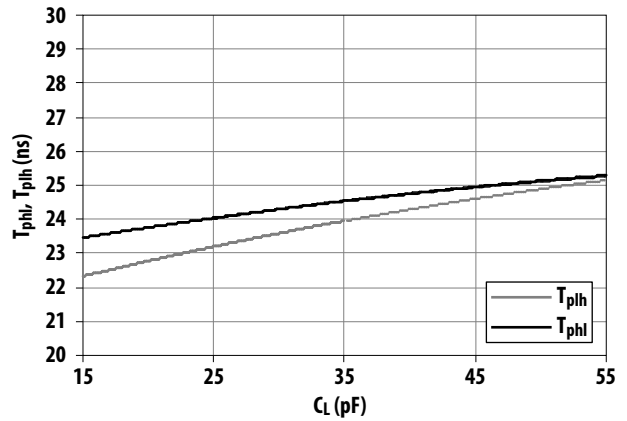


Figure 7: Typical Pulse Width Distortion vs Temperature at 3.3V Supply Voltage

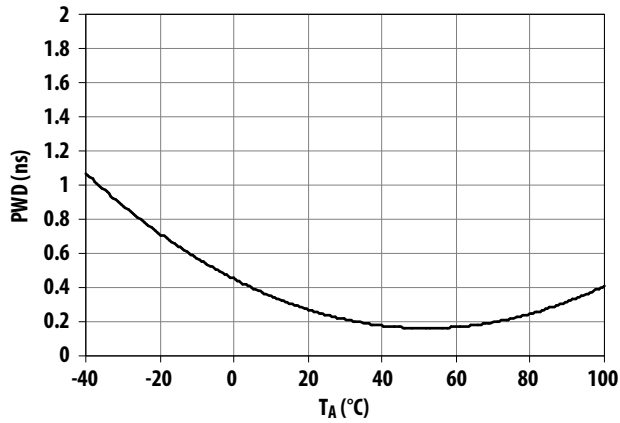


Figure 8: Typical Pulse Width Distortion vs Load Capacitance at 3.3V Supply Voltage

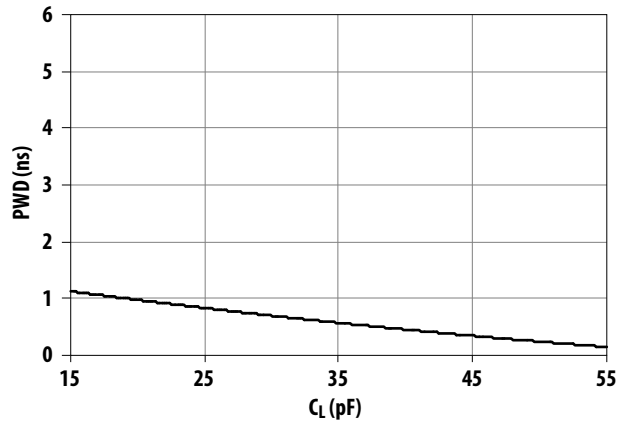


Figure 9: Typical Rise and Fall Time vs Temperature at 3.3V Supply Voltage

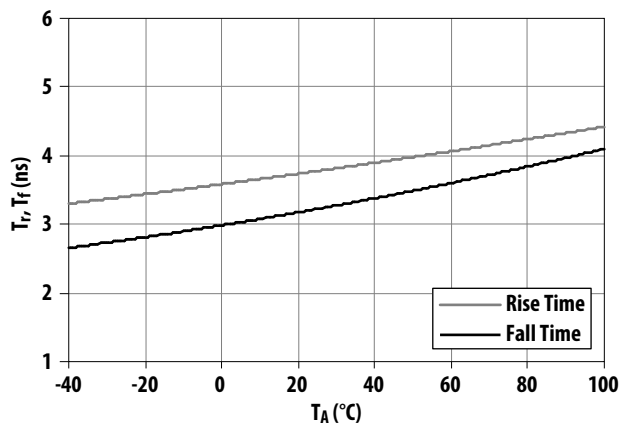
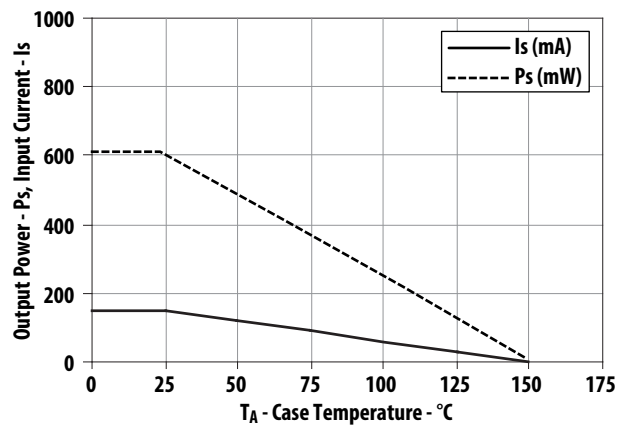


Figure 10: Thermal Derating Curve, Dependence of Safety Limiting Value with Case Temperature per IEC/EN/DIN EN 60747-5-5



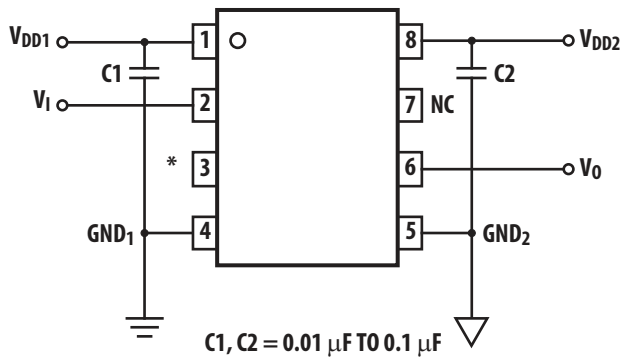
Application Information

Bypassing and PC Board Layout

The ACPL-077L optocoupler is extremely easy to use. No external interface circuitry is required because ACPL-077L uses high-speed CMOS IC technology, allowing CMOS logic to be connected directly to the inputs and outputs.

As shown in [Figure 11](#), the only external components required for proper operation are two bypass capacitors. Capacitor values should be between 0.01 μF and 0.1 μF . Each capacitor should be placed as close as possible to the input and output power-supply pins of the optocoupler.

Figure 11: Recommended Circuit Diagram



- * Pin 3 is multiplexed as a test pin that can connect to VDD or left unconnected. Pin 7 is not connected internally.

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